Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination CHANG ET AL.	
10/708,489		
Examiner	Art Unit	
Y. J. Han	2838	

SEARCHED					
Class	Subclass	Date	Examiner		
323	312				
	313				
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	274				
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327	530				
	534				
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Search	updated	6/20/2007	JH		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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See sear	ch report	6/25/2007	JH	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
•	DATE	EXMR		
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